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PTO/SB/08a/b (07-05)

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Substitute for form 1449A/B/PTO				Complete if Known 107560302	
				Application Number	Not Yet Assigned
				Filing Date	Concurrently Herewith
				First Named Inventor	Markus Schafheutle
				Art Unit	N/A
				Examiner Name	Not Yet Assigned
Sheet	1	of	2	Attorney Docket Number	11885-00072-US

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ - Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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BK	EP-0 649 865	04-26-1995	Hoechst Aktiengesellschaft		See US 5,571,861 and US 5,623,016
BL	DE-196 18 675	03-27-1997	BASF AG		See Abstract

Examiner Signature	<i>Patrick J. M.</i>	Date Considered	3/27/07
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				Art Unit	N/A
				Examiner Name	Not Yet Assigned
Sheet	2	of	2	Attorney Docket Number	11885-00072-US

<i>PR</i>	BM	EP-0 844 261	05-27-1998	BASF Aktiengesellschaft		See Abstract
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NON PATENT LITERATURE DOCUMENTS							
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue .number(s), publisher, city and/or country where published.					T ²

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Examiner Signature	<i>Patrick J. H. D.</i>	Date Considered	3/27/07
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